Se	Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/467,611	MIAO ET AL.	
Examiner	Art Unit	-
Jason M. Perilla	2611	

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	295	11/6/2006	JP .
	316	11/6/2006	JP
	346	11/6/2006	JP

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
East USPAT/USPGPUB	11/6/2006	JP
Inventor Name Search EAST/EDAN	11/6/2006	JP